

Statistical Machine Learning (BE4M33SSU)

Lecture 2: Empirical Risk

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Definition of the prediction problem

- ◆ \mathcal{X} is a set of input observations/features
- ◆ \mathcal{Y} is a set of hidden states
- ◆ $(x, y) \in \mathcal{X} \times \mathcal{Y}$ samples randomly drawn from r.v. with p.d.f. $p(x, y)$
- ◆ $h: \mathcal{X} \rightarrow \mathcal{Y}$ is a prediction strategy/hypothesis
- ◆ $\ell: \mathcal{Y} \times \mathcal{Y} \rightarrow \mathbb{R}$ is a loss function
- ◆ Task: find a **strategy with the minimal true risk** (expected loss)

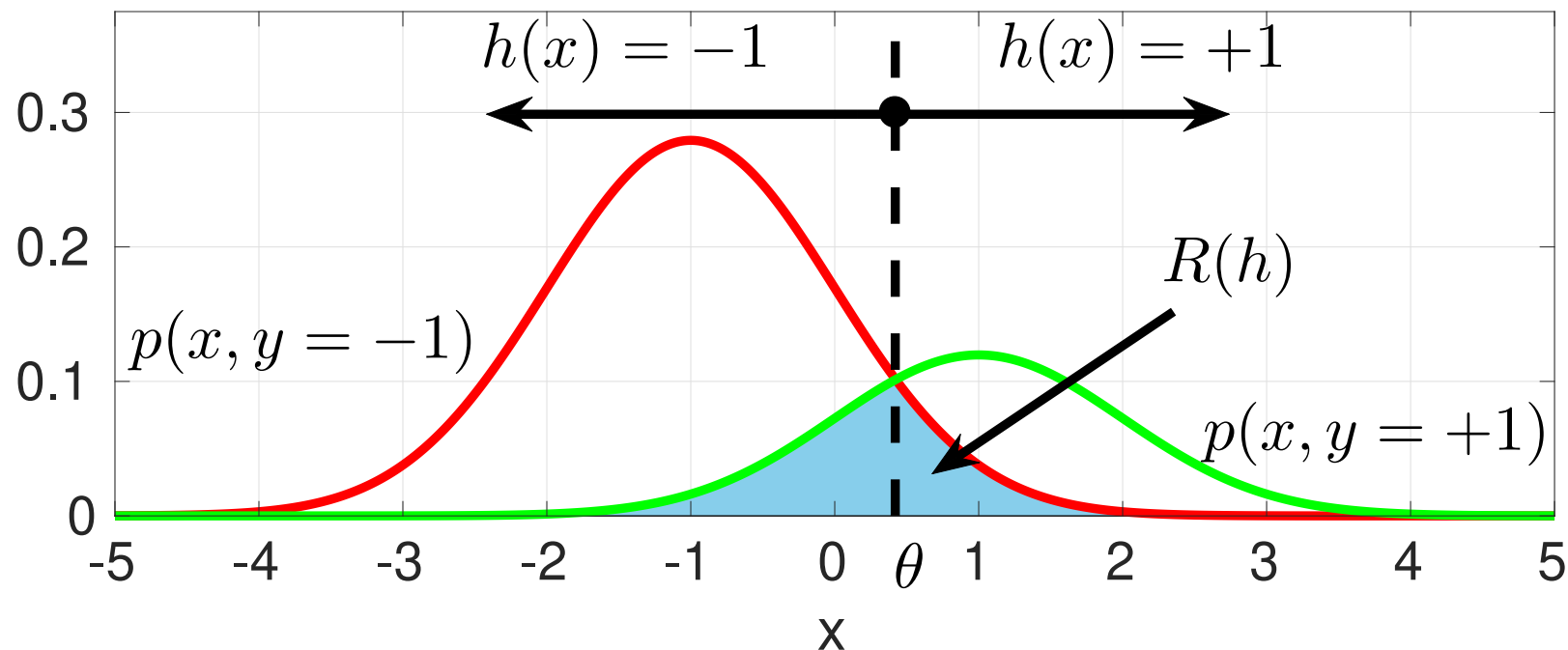
$$R(h) = \int \sum_{y \in \mathcal{Y}} \ell(y, h(x)) p(x, y) dx = \mathbb{E}_{(x, y) \sim p}(\ell(y, h(x)))$$

- ◆ **Bayes predictor** h^* attains the minimal risk $R(h^*) = \inf_{h \in \mathcal{Y}^{\mathcal{X}}} R(h)$

Example of a prediction problem

◆ The statistical model is known:

- $\mathcal{X} = \mathbb{R}$, $\mathcal{Y} = \{+1, -1\}$, $\ell(y, y') = \begin{cases} 0 & \text{if } y = y' \\ 1 & \text{if } y \neq y' \end{cases}$
- $p(x, y) = p(y) \frac{1}{\sqrt{2\pi}\sigma} e^{-\frac{1}{2\sigma^2}(x-\mu_y)^2}$, $y \in \mathcal{Y}$.



Machine Learning: solving the prediction problem based on examples

- ◆ **Assumption:** we have an access to examples

$$\{(x^1, y^1), (x^2, y^2), \dots\}$$

drawn from i.i.d. r.v. distributed according to **unknown** $p(x, y)$.

- ◆ 1) **Evaluation:** estimate true risk $R(h)$ of given $h: \mathcal{X} \rightarrow \mathcal{Y}$ using **test set**

$$\mathcal{S}^l = \{(x^i, y^i) \in (\mathcal{X} \times \mathcal{Y}) \mid i = 1, \dots, l\}$$

drawn i.i.d. from $p(x, y)$.

- ◆ 2) **Learning:** find $h: \mathcal{X} \rightarrow \mathcal{Y}$ with small $R(h)$ using **training set**

$$\mathcal{T}^m = \{(x^i, y^i) \in (\mathcal{X} \times \mathcal{Y}) \mid i = 1, \dots, m\}$$

drawn i.i.d. from $p(x, y)$.

Evaluation: estimation of the expected risk

- ◆ Given a predictor $h: \mathcal{X} \rightarrow \mathcal{Y}$ and a test set \mathcal{S}^l draw i.i.d. from distribution $p(x, y)$, compute the **empirical risk**

$$R_{\mathcal{S}^l}(h) = \frac{1}{l} (\ell(y^1, h(x^1)) + \dots + \ell(y^l, h(x^l))) = \frac{1}{l} \sum_{i=1}^l \ell(y^i, h(x^i))$$

and use it as an estimate of $R(h) = \mathbb{E}_{(x,y) \sim p}(\ell(y, h(x)))$.

- ◆ $R_{\mathcal{S}^l}(h)$ is a random number with the variance depending on l .
- ◆ We construct a **confidence interval** such that

$$R(h) \in (R_{\mathcal{S}^l(h)} - \varepsilon, R_{\mathcal{S}^l(h)} + \varepsilon) \quad \text{with probability (confidence) } \gamma \in (0, 1)$$

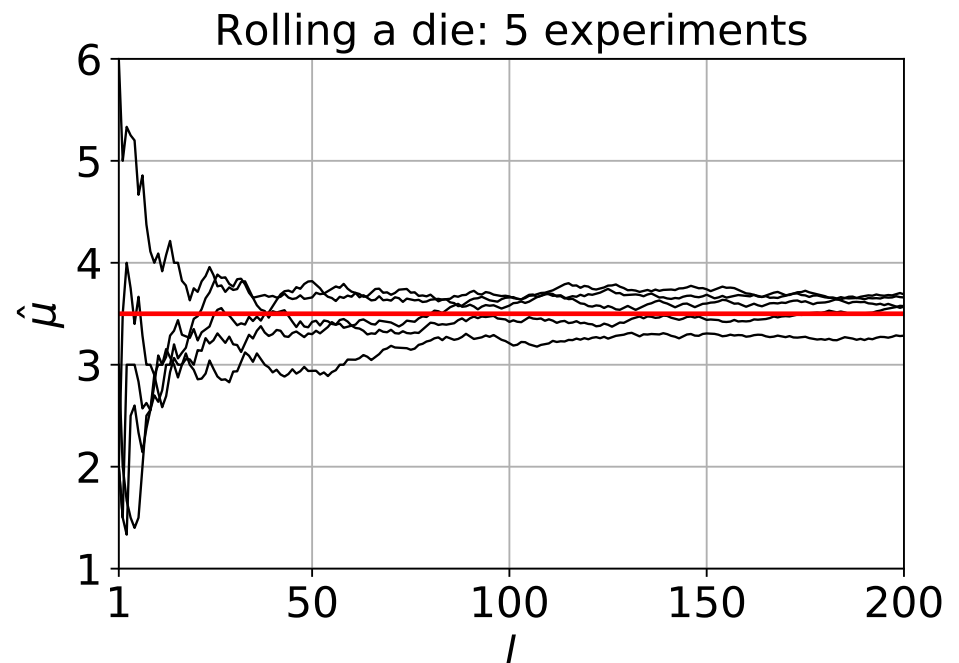
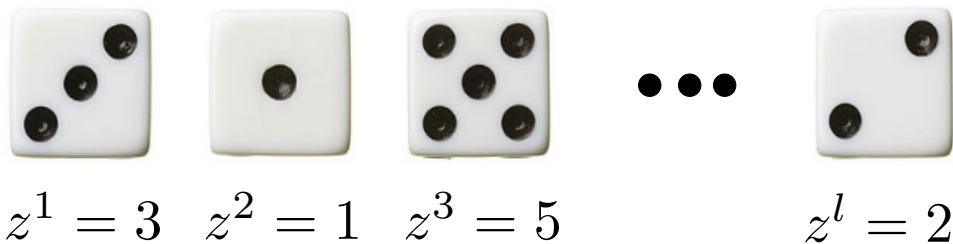
where ε is a deviation.

Law of large numbers

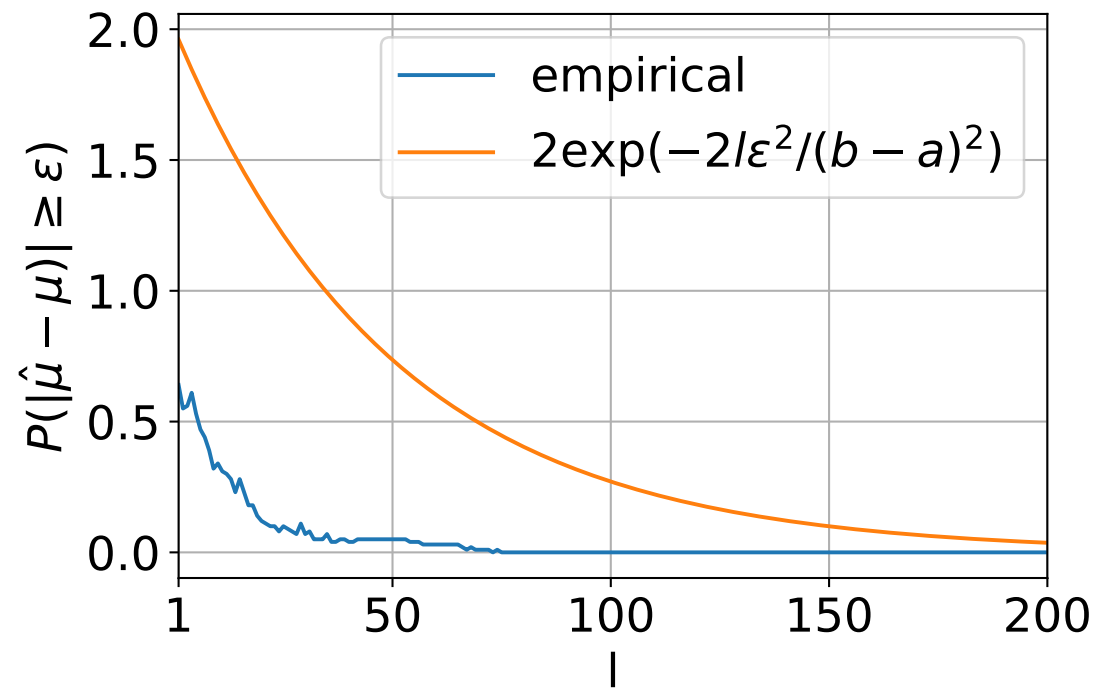
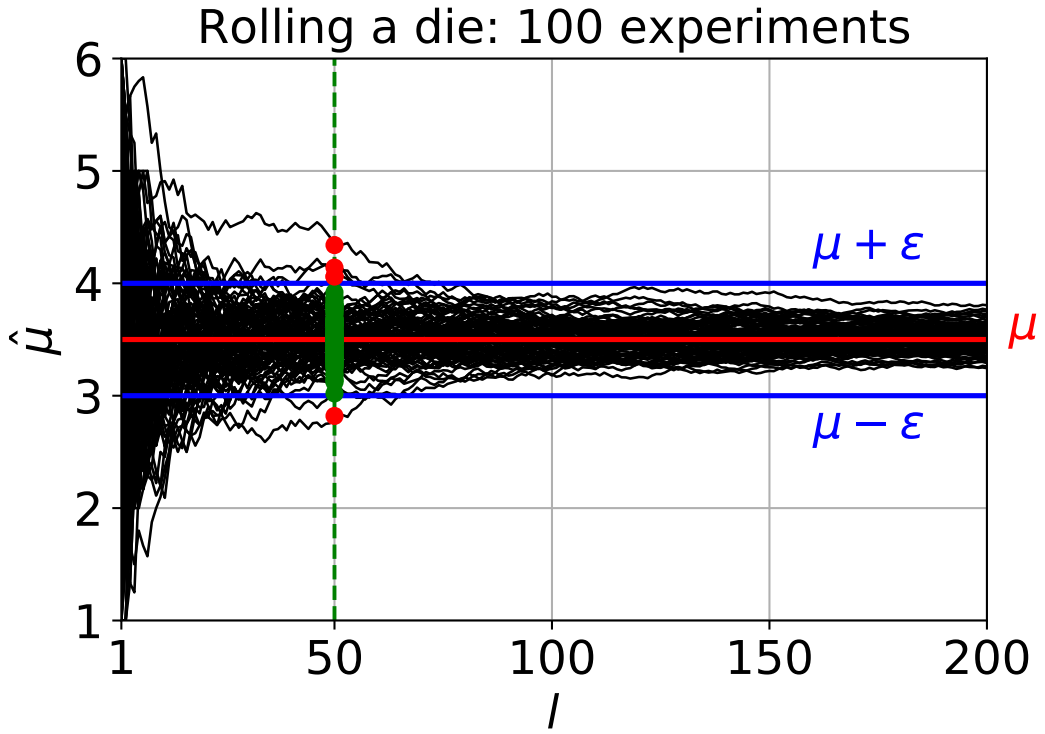
- ◆ Sample mean (arithmetic average) of the results of random trials gets closer to the expected value as more trials are performed.
- ◆ Example: The expected value of a single roll of a fair die is

$$\mu = \mathbb{E}_{z \sim p}(z) = \sum_{z=1}^6 z p(z) = \frac{1 + 2 + 3 + 4 + 5 + 6}{6} = 3.5$$

$$\hat{\mu} = \frac{1}{l} \sum_{i=1}^l z^i$$



Counting frequency of bad estimates



sample size $l = 50$, deviation $\epsilon = 0.5$

Hoeffding inequality

$$\frac{\#(|\hat{\mu} - \mu| \geq \epsilon)}{\#\text{experiments}} = \frac{5}{100} = 0.05 \quad \rightarrow \quad \mathbb{P}\left(|\hat{\mu} - \mu| \geq \epsilon\right) \leq 2e^{-\frac{2l\epsilon^2}{(b-a)^2}}$$

$$a = 1, b = 6$$

Hoeffding inequality

Theorem: Let $\{z^1, \dots, z^l\}$ be a sample from i.i.d. r.v. from $[a, b]$ with expected value μ . Let $\hat{\mu} = \frac{1}{l} \sum_{i=1}^l z^i$. Then for any $\varepsilon > 0$ it holds that

$$\mathbb{P}\left(|\hat{\mu} - \mu| \geq \varepsilon\right) \leq 2e^{-\frac{2l\varepsilon^2}{(b-a)^2}}$$

Properties:

- ◆ Conservative: the bound may not be tight.
- ◆ General: the bound holds for any distribution.
- ◆ Cheap: The bound is simple and easy to compute.

Confidence intervals

$$(l, \gamma) \rightarrow \varepsilon$$

- ◆ Let $\hat{\mu} = \frac{1}{l} \sum_{i=1}^l z^i$ be the sample mean computed from $\{z^1, \dots, z^l\} \in [a, b]^l$ sampled from r.v. with expected value μ .
- ◆ Find ε such that $\mu \in (\hat{\mu} - \varepsilon, \hat{\mu} + \varepsilon)$ with probability at least γ .

Using the Hoeffding inequality we can write

$$\mathbb{P}\left(|\hat{\mu} - \mu| < \varepsilon\right) = 1 - \mathbb{P}\left(|\hat{\mu} - \mu| \geq \varepsilon\right) \geq 1 - 2e^{-\frac{2l\varepsilon^2}{(b-a)^2}} = \gamma$$

and solving the last equation for ε yields

$$\varepsilon = |b - a| \sqrt{\frac{\log(2) - \log(1 - \gamma)}{2l}}$$

Confidence intervals

$$(\varepsilon, \gamma) \rightarrow l$$

- ◆ Let $\hat{\mu} = \frac{1}{l} \sum_{i=1}^l z^i$ be the sample mean computed from $\{z^1, \dots, z^l\} \in [a, b]^l$ sampled from r.v. with expected value μ .
- ◆ Given a fixed $\varepsilon > 0$ and $\gamma \in (0, 1)$, what is the minimal number of examples l such that $\mu \in (\hat{\mu} - \varepsilon, \hat{\mu} + \varepsilon)$ with probability γ at least ?

Starting from

$$\mathbb{P}\left(|\hat{\mu} - \mu| < \varepsilon\right) = 1 - \mathbb{P}\left(|\hat{\mu} - \mu| \geq \varepsilon\right) \geq 1 - 2e^{-\frac{2l\varepsilon^2}{(b-a)^2}} = \gamma$$

and solving for l yields

$$l = \frac{\log(2) - \log(1 - \gamma)}{2\varepsilon^2} (b - a)^2$$

Evaluation: estimation of the true risk

- ◆ Given $h: \mathcal{X} \rightarrow \mathcal{Y}$ estimate the true risk $R(h) = \mathbb{E}_{(x,y) \sim p}(\ell(y, h(x)))$ by the empirical risk $R_{\mathcal{S}^l}(h) = \frac{1}{l} \sum_{i=1}^l \ell(y^i, h(x^i))$ using the test set \mathcal{S}^l .
- ◆ The incurred losses $z^i = \ell(y^i, h(x^i)) \in [\ell_{\min}, \ell_{\max}]$, $i \in \{1, \dots, l\}$, are realizations of i.i.d. r.v. with the expected value $\mu = R(h)$.
- ◆ According to the Hoeffding inequality, for any $\varepsilon > 0$ the probability of seeing a “bad test set” can be bound by

$$\mathbb{P}\left(\left|R_{\mathcal{S}^l}(h) - R(h)\right| \geq \varepsilon\right) \leq 2e^{-\frac{2l\varepsilon^2}{(\ell_{\min} - \ell_{\max})^2}}$$

- ◆ **Remark:** For any $p(x, y)$ and $\ell: \mathcal{Y} \times \mathcal{Y} \rightarrow [\ell_{\min}, \ell_{\max}]$, the empirical risk $R_{\mathcal{S}^l}(h)$ converges in probability to the true risk $R(h)$:

$$\forall \varepsilon > 0: \lim_{l \rightarrow \infty} \mathbb{P}\left(\left|R_{\mathcal{S}^l}(h) - R(h)\right| \geq \varepsilon\right) = 0$$

Evaluation: recipe for constructing confidence intervals

- ◆ Given $h: \mathcal{X} \rightarrow \mathcal{Y}$ estimate the true risk $R(h) = \mathbb{E}_{(x,y) \sim p}(\ell(y, h(x)))$ by the empirical risk $R_{\mathcal{S}^l}(h) = \frac{1}{l} \sum_{i=1}^l \ell(y^i, h(x^i))$ using the test set \mathcal{S}^l .

- ◆ Confidence interval:

$$R(h) \in (R_{\mathcal{S}^l}(h) - \varepsilon, R_{\mathcal{S}^l}(h) + \varepsilon) \quad \text{with probability } \gamma \in (0, 1)$$

- ◆ For fixed l and $\gamma \in (0, 1)$ compute interval width

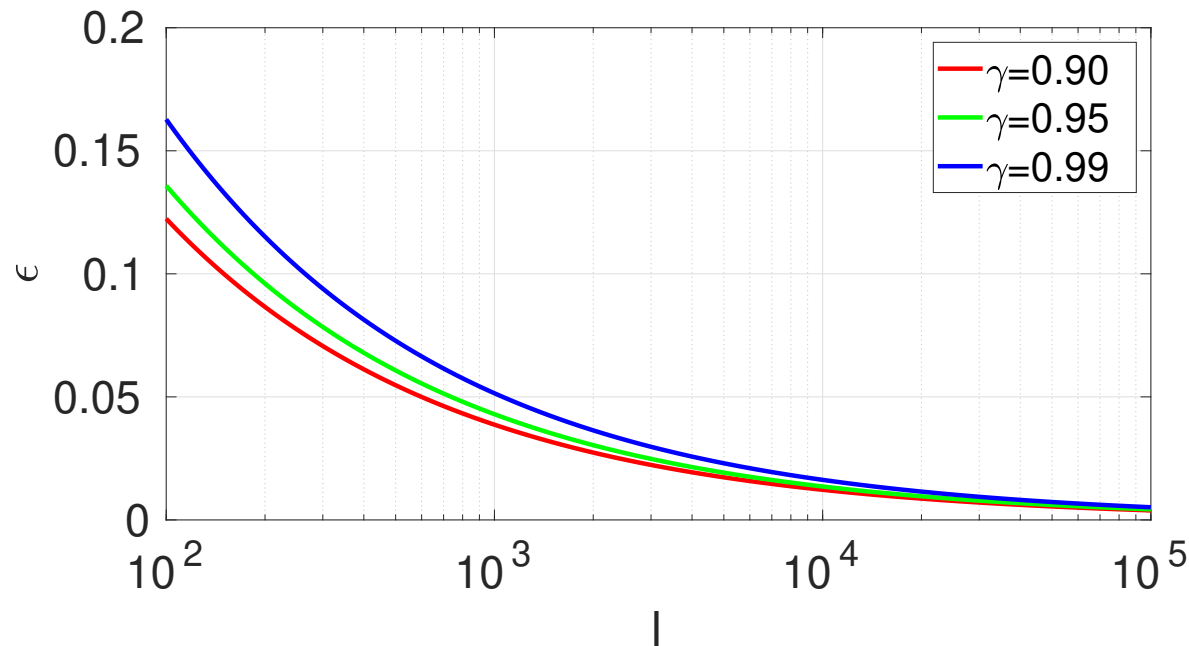
$$\varepsilon = (\ell_{\max} - \ell_{\min}) \sqrt{\frac{\log(2) - \log(1 - \gamma)}{2l}}.$$

- ◆ For fixed ε and $\gamma \in (0, 1)$ compute number of test examples

$$l = \frac{\log(2) - \log(1 - \gamma)}{2\varepsilon^2} (\ell_{\max} - \ell_{\min})^2$$

Example: confidence intervals for classification error

- ◆ The width of $R(h) \in (R_{S^l}(h) - \varepsilon, R_{S^l}(h) + \varepsilon)$ is for $\ell(y, y') = [y \neq y']$ given by $\varepsilon = \sqrt{\frac{\log(2) - \log(1-\gamma)}{2l}}$



for $\gamma = 0.95$

l	100	1,000	10,000	18,445
ε	0.135	0.043	0.014	0.01

- ◆ Example: $l = 10,000$, $R_{S^l}(h) = 0.162$, then classification error is $16.2 \pm 1.4\%$ with confidence 95%.